

# Selectivity of doping ions to effectively improve dielectric and non-ohmic properties of $\text{CaCu}_3\text{Ti}_4\text{O}_{12}$ ceramics

Somsack Vangchangyia<sup>a</sup>, Teerapon Yamwong<sup>b</sup>, Ekaphan Swatsitang<sup>c</sup>,  
Prasit Thongbai<sup>c,d,\*</sup>, Santi Maensiri<sup>e</sup>

<sup>a</sup>Materials Science and Nanotechnology Program, Faculty of Science, Khon Kaen University, Khon Kaen 40002, Thailand

<sup>b</sup>National Metal and Materials Technology Center (MTEC), Thailand Science Park, Pathumthani 12120, Thailand

<sup>c</sup>Department of Physics, Faculty of Science, Khon Kaen University, Khon Kaen 40002, Thailand

<sup>d</sup>Integrated Nanotechnology Research Center (INRC), Khon Kaen University, Khon Kaen 40002, Thailand

<sup>e</sup>School of Physics, Institute of Science, Suranaree University, Nakhon Ratchasima 30000, Thailand

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## Abstract

We provide two separate strategies to improve the dielectric properties of  $\text{CaCu}_3\text{Ti}_4\text{O}_{12}$  ceramics. First, substitution of  $\text{La}^{3+}$  ions can reduce the loss tangent ( $\tan\delta < 0.03$ ) and increase the temperature stability of the dielectric constant ( $\Delta\epsilon'(\%)$ ) of  $\text{CaCu}_3\text{Ti}_4\text{O}_{12}$  ceramics. The dielectric constant of  $\text{CaCu}_3\text{Ti}_4\text{O}_{12}$  was greatly reduced from  $\sim 17500$  to  $\sim 5300$  and  $\sim 2700$  for  $\text{Ca}_{0.775}\text{La}_{0.15}\text{Cu}_3\text{Ti}_4\text{O}_{12}$  and  $\text{Ca}_{0.70}\text{La}_{0.2}\text{Cu}_3\text{Ti}_4\text{O}_{12}$ , respectively. The  $\Delta\epsilon'(\%)$  values of these two ceramics were found to be approximately  $\pm 15\%$  over the temperature ranges of  $-55$ – $125$  °C and  $-55$ – $150$  °C, meeting X7R and X8R temperature characteristics for capacitor applications, respectively. Second, substitution of  $\text{Sr}^{2+}$  at concentrations of 5–15 at% can significantly reduce  $\tan\delta$  ( $< 0.04$ ). Interestingly, the dielectric constant decreased slightly and was found to be higher than  $10^4$ . However, the requirement for  $\Delta\epsilon' < \pm 15\%$  was obtained only over the  $-60$ – $90$  °C temperature range. The effects of  $\text{La}^{3+}$  and  $\text{Sr}^{2+}$  doping ions on the nonlinear current–voltage properties were also investigated. Both doping ions were observed to significantly enhance nonlinear electrical properties.

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## 1. Introduction

In recent years, the demand for electronic components that can be operated at high temperatures has dramatically increased due to rapid development of new technologies. One result is that sizes of electronic components have to be smaller. This is needed to support new technologies requiring low-weight electronic devices and/or to increase functions of communication devices such as smartphones. Among basic electronic components, multilayer ceramic capacitors (MLCCs) are widely used as passive components in electronic

systems [1]. New dielectric materials with better performance and lower costs have therefore gained attention [2–14]. Usually, three basic factors are considered to determine suitability of a material for use in fabrication of MLCCs. These are the values of a dielectric constant ( $\epsilon'$ ), the loss tangent ( $\tan\delta$ ), and the temperature stability of  $\epsilon'$  ( $\Delta\epsilon'(\%)$ ) or the temperature stability of capacitance ( $\Delta C/C_{25}(\%)$ ) [15].

Since giant dielectric properties of  $\text{CaCu}_3\text{Ti}_4\text{O}_{12}$  (CCTO) were discovered [10], CCTO has been intensively investigated [11,16–36]. CCTO ceramics can exhibit very high  $\epsilon'$  values, in the range of  $10^3$ – $10^5$ , depending on microstructure and sintering conditions. Unfortunately,  $\tan\delta$  of CCTO ceramics was found to be higher than 0.05 at room temperature and a frequency of  $10^3$  Hz, which is too large. Many investigations focused on strategies to reduce the value of  $\tan\delta$  while retaining a high  $\epsilon'$  value [16,22,25,27–31,35]. Most researchers believe that high  $\tan\delta$  values are a serious problem that prevents

\*Corresponding author at: Department of Physics, Faculty of Science, Khon Kaen University, Khon Kaen 40002, Thailand.

Tel.: +66 84 4190266; fax: +66 43 202374.

E-mail addresses: [prasitphysics@hotmail.com](mailto:prasitphysics@hotmail.com),  
[pthongbai@kku.ac.th](mailto:pthongbai@kku.ac.th) (P. Thongbai).

practical applications of CCTO ceramics. In MLCCs, the temperature coefficient of capacitance (or  $\epsilon'$ ) of a dielectric material is one of the most important factors that must be considered [15]. For an X7R capacitor,  $\Delta\epsilon'(\%)$  or  $\Delta C/C_{25}(\%)$  (compared to the  $\epsilon'$  value at 25 °C and  $10^3$  Hz) of a dielectric material used to fabricate this type of capacitor must be less than  $\pm 15\%$  over the temperature range of  $-55$ – $125$  °C. This is necessary to achieve capacitance values that vary less than  $\pm 15\%$  with temperature over this range. For X5R and X8R capacitors,  $\Delta\epsilon'(\%)$  has to be less than  $\pm 15\%$  over the ranges of  $-55$ – $85$  °C and  $-55$ – $150$  °C, respectively [15].

It was also found that substitution of  $\text{La}^{3+}$  or  $\text{Sr}^{2+}$  into CCTO ceramics can improve the dielectric properties of CCTO ceramics [25,28]. For instance,  $\tan\delta$  of CCTO ceramics substituted by  $\text{La}^{3+}$  ions was significantly reduced to a value of 0.03 [25]. Substitution of  $\text{Sr}^{2+}$  ions into CCTO ceramics can greatly reduce  $\tan\delta$  while retaining a high  $\epsilon'$  value [28]. This suggests that  $\text{La}^{3+}$  and  $\text{Sr}^{2+}$ -doped CCTO ceramic materials have high potential for use in practical applications as capacitive elements. Unfortunately, systematic investigations to study the possibility for practical capacitor application of these materials have rarely been done. The effects of  $\text{La}^{3+}$  or  $\text{Sr}^{2+}$  doping concentrations on the values of  $\epsilon'$  and  $\tan\delta$  as well as the temperature coefficient of capacitance must be investigated before practical developments are possible. According to previous work [18,31], CCTO ceramics prepared using Ca- and Cu-acetates exhibited interesting dielectric properties including high  $\epsilon'$  and low  $\tan\delta$ . The results revealed that CCTO ceramics prepared using these raw materials may have potential for capacitor applications. We hypothesized that metal ions substituted to CCTO ceramics prepared using Ca- and Cu-acetates as starting raw materials may provide good dielectric properties, especially for  $\text{La}^{3+}$  and  $\text{Sr}^{2+}$ -doped CCTO ceramics. Thus, we prepared  $\text{La}^{3+}$  and  $\text{Sr}^{2+}$ -doped CCTO ceramics using a simple thermal decomposition method. Ca- and Cu-acetates were used as sources of  $\text{Ca}^{2+}$  and  $\text{Cu}^{2+}$  ions, respectively. The influences of these doping ions on the dielectric properties and nonlinear current–voltage properties of CCTO ceramics were investigated.

## 2. Experimental details

$\text{Ca}_{1-3x/2}\text{La}_x\text{Cu}_3\text{Ti}_4\text{O}_{12}$  and  $\text{Ca}_{1-x}\text{Sr}_x\text{Cu}_3\text{Ti}_4\text{O}_{12}$  ceramics, where  $x=0.05, 0.10, 0.15$ , and  $0.20$  (referred to as La05, La10, La15, La20 samples and Sr05, Sr10, Sr15, Sr20 samples, respectively), were prepared using a simple thermal decomposition method. Undoped  $\text{CaCu}_3\text{Ti}_4\text{O}_{12}$  was referred to as the CCTO sample.  $\text{Ca}(\text{C}_2\text{H}_3\text{CO}_2)_2 \cdot \text{H}_2\text{O}$  (99+%, Sigma-Aldrich),  $\text{Cu}(\text{CH}_3\text{COO})_2 \cdot \text{H}_2\text{O}$  (98–102.0%, Carlo Erba),  $\text{C}_{16}\text{H}_{28}\text{O}_6\text{Ti}$  (75 wt% in isopropanol, Sigma-Aldrich),  $(\text{C}_2\text{H}_3\text{O}_2)_2\text{Sr}$  (99.995%, Sigma-Aldrich),  $(\text{C}_6\text{H}_9\text{O}_6)\text{La} \cdot x\text{H}_2\text{O}$  (99.9%, Sigma-Aldrich), citric acid, and ethanol were employed as starting raw materials. Details of the preparation were previously reported [31]. Mixed solutions of each composition were reacted at 900 °C for 4 h. The resulting powders were ground and pressed into pellets using a 9.5 mm diameter die set, samples of  $\sim 1$ – $2$  mm in thickness were

obtained by uniaxial compression at 200 MPa. Finally, these disks were sintered in air at 1070 °C for 9 h.

X-ray diffraction (XRD; Philips PW3040, the Netherlands) and scanning electron microscopy (SEM; Hitachi S-3400, Japan) were used to characterize the phase composition and microstructure of the sintered  $\text{CaCu}_3\text{Ti}_4\text{O}_{12}$  ceramics. The dielectric response of the samples was measured using an Agilent E4980A (Hayward, CA) Precision LCR Meter over the frequency and temperature ranges of  $10^2$ – $10^6$  Hz and  $-70$ – $150$  °C, respectively. An oscillation voltage of 0.5 V was used in each case. Each temperature was held constant with an accuracy of  $\pm 1$  °C. Current–voltage measurements were made using a high voltage measurement unit (Keithley Model 247, Estado St Pasadena, CA). The breakdown electric field ( $E_b$ ) was achieved at  $J=1 \text{ mA cm}^{-2}$ . The nonlinear coefficient ( $\alpha$ ) was calculated from the following formula:

$$\alpha = \frac{\log(J_2/J_1)}{\log(E_2/E_1)}, \quad (1)$$

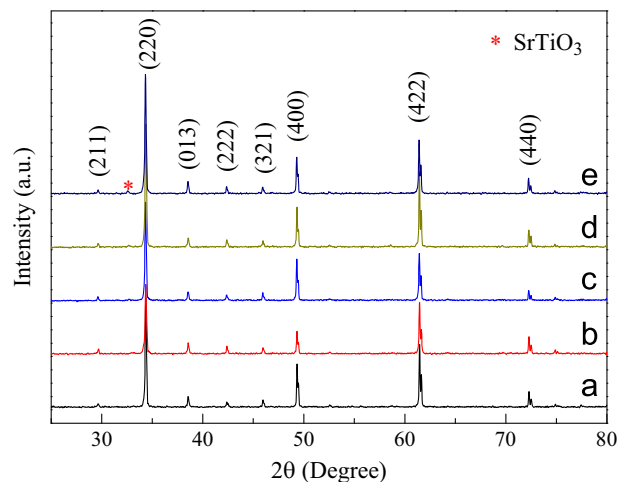


Fig. 1. XRD patterns of (a) CCTO, (b) Sr05, (c) Sr10, (d) Sr15, and (e) Sr20 ceramic samples.

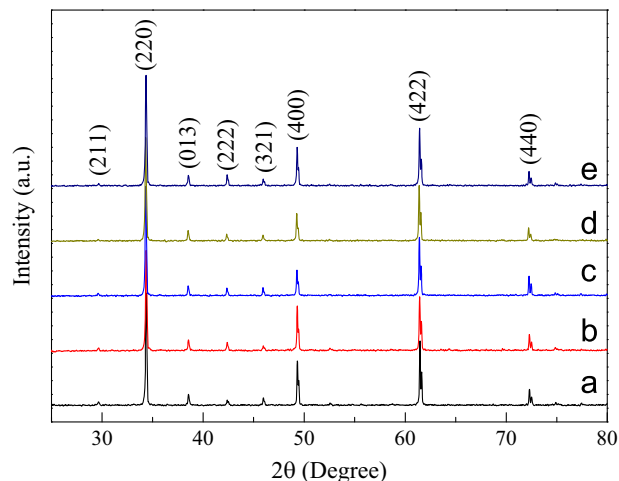


Fig. 2. XRD patterns of (a) CCTO, (b) La05, (c) La10, (d) La15, and (e) La20 ceramic samples.

where  $E_1$  and  $E_2$  are, respectively, the electric fields corresponding to  $J_1=1$  and  $J_2=10$  mA cm<sup>-2</sup>. Prior to measurements, Au was sputtered onto each pellet face at a current of 25 mA for 8 min using a Polaron SC500 (Sussex, UK) sputter coating unit.

### 3. Results and discussion

Figs. 1 and 2 show the XRD patterns of Sr<sup>2+</sup>- and La<sup>3+</sup>-doped CCTO ceramics, respectively. All of the XRD patterns exhibited the main phase of CCTO with centered-cubic perovskite structure. Pure phase of CCTO was detected

in the XRD patterns of all compositions of La<sup>3+</sup>-doped CCTO ceramics without impurity phases. This result is similar to those in published literature [25]. The second phase of SrTiO<sub>3</sub> was only observed in the XRD pattern of the Sr20 sample. Other Sr<sup>2+</sup>-doped CCTO samples showed only the pure phase. This observation of Sr<sup>2+</sup>-doped CCTO ceramics prepared using a thermal decomposition method is consistent with Sr<sup>2+</sup>-doped CCTO ceramics prepared using a solid state reaction method [28]. Lattice parameters of the CCTO, Sr05, Sr10, Sr15, and Sr20 samples were calculated and found to be 7.392, 7.393, 7.392, 7.392, and 7.396 Å, respectively. Lattice parameters of the La05, La10, La15, and La20 samples were calculated to be 7.394, 7.394,

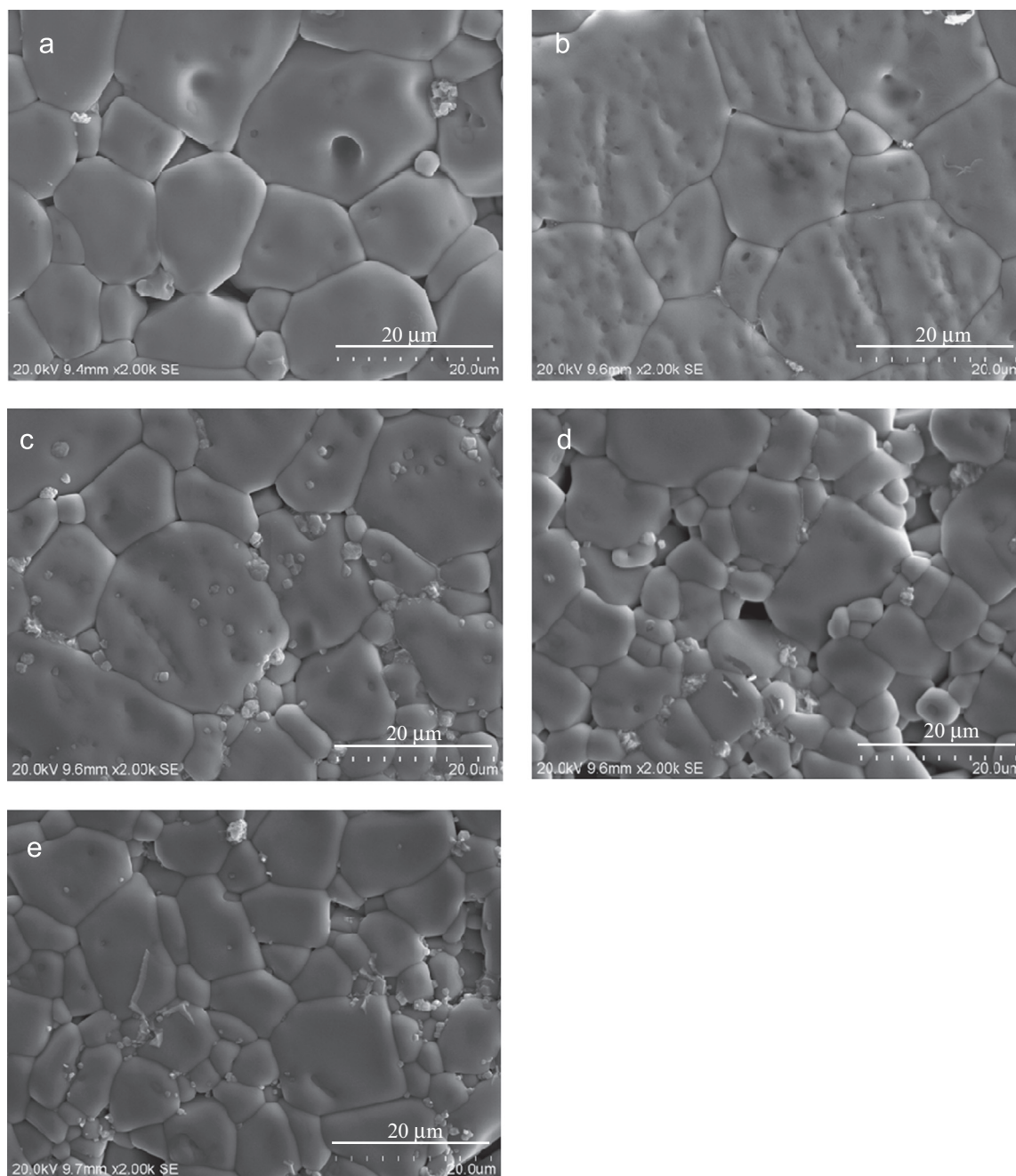


Fig. 3. SEM images of polished surface morphologies of (a) CCTO, (b) Sr05, (c) Sr10, (d) Sr15, and (e) Sr20 ceramic samples.



7.398, and 7.398 Å, respectively. The lattice parameter of the  $\text{La}^{3+}$ -doped CCTO ceramics significantly increased as the concentration of  $\text{La}^{3+}$  increased. The lattice parameters of the Sr05, Sr10, and Sr15 samples were nearly constant compared to that of the CCTO sample. The lattice parameter of the Sr20 sample increased significantly.

Fig. 3 shows surface morphologies of the CCTO and  $\text{Sr}^{2+}$ -doped CCTO ceramics, revealing grain and grain boundary (GB) microstructure. The mean grain size of CCTO ceramics increased slightly when doping with 5 at%  $\text{Sr}^{2+}$  for the Sr05 sample. Then it gradually decreased as the concentration of  $\text{Sr}^{2+}$  doping ions increased from 10 to 20 at%. This result is similar to that found in published reports [28]. The microstructures of the  $\text{La}^{3+}$ -doped CCTO ceramics are shown in Fig. 4. Low concentration of  $\text{La}^{3+}$  doping content in the La05 sample has no significant influence on the microstructure of CCTO ceramics. With increasing  $\text{La}^{3+}$  doping content, the mean grain size was greatly decreased. This decrease in the mean grain size of  $\text{La}^{3+}$ -doped CCTO may be attributed to the ability of  $\text{La}^{3+}$  doping ions to inhibit the GB mobility during the sintering process. Note that porosity is observed in the La10, La15, and La20 samples.

Fig. 5a and c shows  $\epsilon'$  values at 20 °C as a function of frequency for the  $\text{La}^{3+}$ - and  $\text{Sr}^{2+}$ -doped CCTO ceramics.  $\epsilon'$  of the CCTO and La05 samples gradually decreased as the frequency increased. Frequency independence of  $\epsilon'$  over the measured range was observed in the La10, La15, and La20

samples. It was found that  $\epsilon'$  of the  $\text{La}^{3+}$ -doped CCTO ceramics decreased with increasing  $\text{La}^{3+}$  doping concentration. For the  $\text{Sr}^{2+}$ -doped CCTO ceramics,  $\epsilon'$  decreased continuously as the  $\text{Sr}^{2+}$  doping content increased from 5 to 15 at% for the Sr05, Sr10, and Sr15 samples. Then,  $\epsilon'$  increased slightly when  $\text{Sr}^{2+}$  content was further increased from 15 to 20 at%. The frequency dependence of  $\tan\delta$  for  $\text{La}^{3+}$ - and  $\text{Sr}^{2+}$ -doped CCTO ceramics is shown in Fig. 5b and d, respectively. It was found that low-frequency  $\tan\delta$  values (in the range of  $10^2$ – $10^4$  Hz) for the La05 sample slightly increased compared to the CCTO sample. With increasing  $\text{La}^{3+}$  content, the low-frequency  $\tan\delta$  decreased as  $\text{La}^{3+}$  doping content increased. Substitution of  $\text{Sr}^{2+}$  into CCTO ceramics at concentrations of 5–15 at% (the Sr05, Sr10, and Sr15 samples) greatly decreased the low-frequency  $\tan\delta$ . However, substitution of  $\text{Sr}^{2+}$  at the highest concentration (20 at%) for the Sr20 sample resulted in an increase in  $\tan\delta$ . The  $\tan\delta$  values at 1 kHz of all samples are summarized in Table 1. Interestingly, substitution of  $\text{Sr}^{2+}$  or  $\text{La}^{3+}$  ions with suitable concentrations can greatly reduce  $\tan\delta$ . For  $\text{La}^{3+}$ -doped CCTO ceramics, higher concentrations of  $\text{La}^{3+}$  doping ions are likely suitable. However, for  $\text{Sr}^{2+}$  doping ions, high doping concentration is unsuitable. A small concentration of  $\text{Sr}^{2+}$  is recommended for improving dielectric response in CCTO ceramics prepared using a simple thermal decomposition method. This result is consistent with observations of  $\text{Sr}^{2+}$ -doped CCTO ceramics prepared by a solid state reaction method [28]. The  $\epsilon'$  values at 20 °C and  $10^3$  Hz of all samples

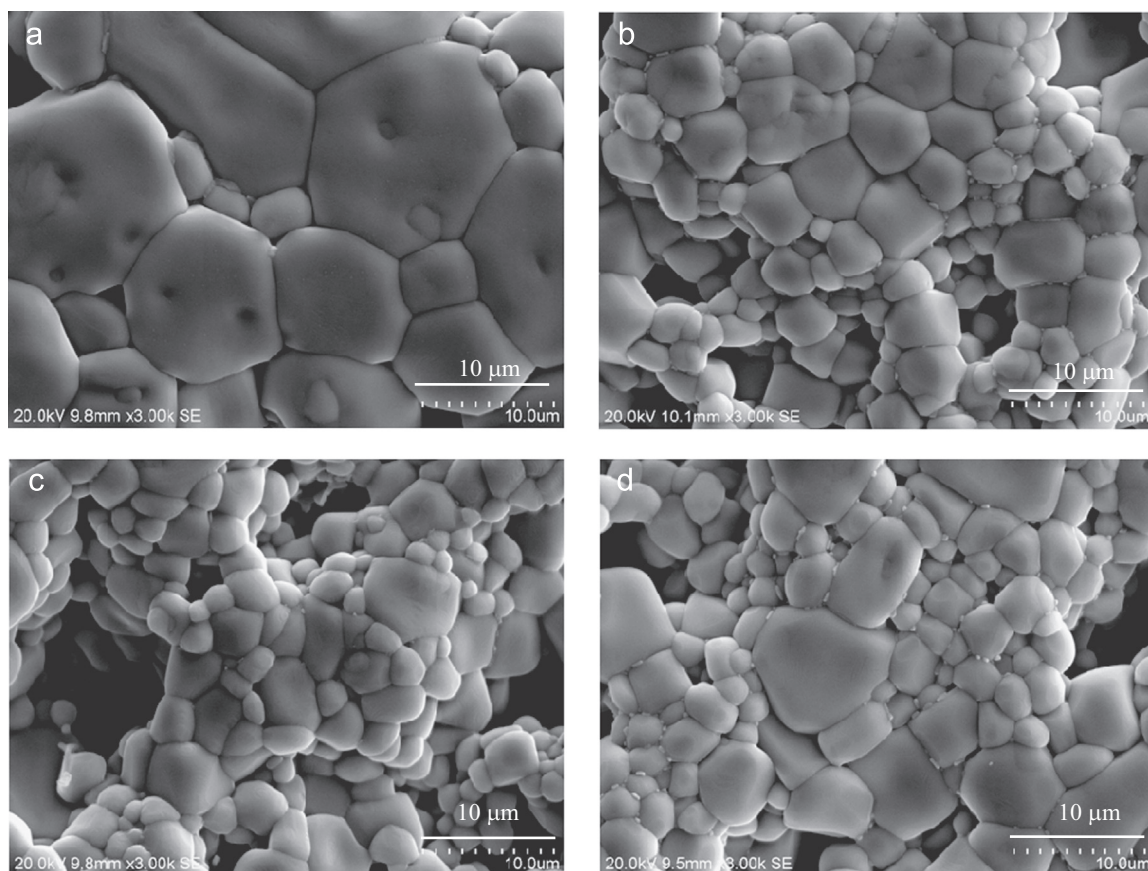


Fig. 4. SEM images of polished surface morphologies of (a) La05, (b) La10, (c) La15, and (d) La20 ceramic samples.

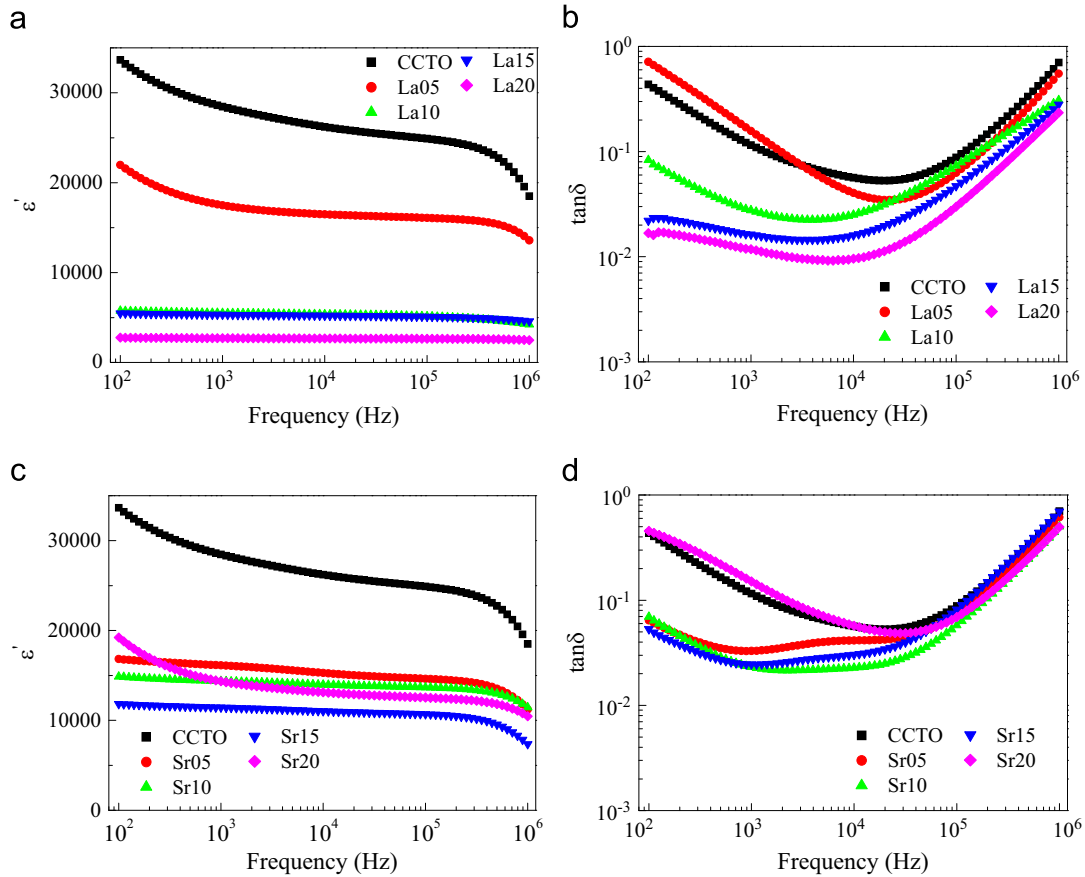


Fig. 5. (a and c) Frequency dependence of  $\epsilon'$  at 20 °C for La-doped CCTO and Sr-doped CCTO ceramics. (b and d) Frequency dependence of  $\tan\delta$  at 20 °C for La-doped CCTO and Sr-doped CCTO ceramics.

Table 1

Dielectric properties ( $\epsilon'$  and  $\tan\delta$  at 20 °C and 1 kHz), temperature coefficient of capacitance ( $\Delta C/C_{20^\circ\text{C}}$  (%)), nonlinear coefficient ( $\alpha$ ), and breakdown field ( $E_b$ ) for the CCTO, La-doped CCTO, and Sr-doped CCTO ceramics.

Sample	$\epsilon'$	$\tan\delta$	$\Delta C/C_{20^\circ\text{C}}$ (%)				$\alpha$	$E_b$ (V cm <sup>-1</sup> )
			−60 °C	90 °C	130 °C	150 °C		
CCTO	28,473	0.116	−11.67	43.85	107.33	173.01	3.53	582
La05	17,498	0.157	−8.50	77.80	128.86	144.01	2.96	562
La10	5,508	0.028	−3.97	13.36	42.64	55.42	6.11	2,832
La15	5,311	0.016	−1.33	5.00	12.21	23.22	6.98	4,149
La20	2,704	0.012	0.28	3.11	7.77	13.67	7.19	5,242
Sr05	16,131	0.033	−8.56	11.80	40.74	49.19	5.02	1,436
Sr10	14,369	0.023	−3.81	15.15	61.89	87.61	5.37	1,850
Sr15	11,432	0.025	−3.82	14.77	69.69	114.76	6.90	3,402
Sr20	14,348	0.151	−11.92	122.71	310.35	370.07	3.53	513

are summarized in Table 1. As reported by Yang et al. [28],  $\tan\delta$  of CCTO ceramics was decreased significantly by substitution of 10 at%  $\text{Sr}^{2+}$ ,  $\tan\delta \sim 0.022$  at 1 kHz. They also found that the GB resistance ( $R_{\text{gb}}$ ) of CCTO ceramics increased when doping with 10 at%  $\text{Sr}^{2+}$ . Thus, we attribute the large decrease in  $\tan\delta$  of  $\text{Sr}^{2+}$ -doped CCTO ceramics to the enhancement of  $R_{\text{gb}}$  as reported by Yang et al. [28].

As shown in Table 1,  $\tan\delta$  values of the La10, La15, and La20 samples were greatly reduced to 0.028, 0.016, and 0.012, respectively.  $\epsilon'$  remained higher than  $10^3$  (at 20 °C and 1 kHz).

These values of  $\epsilon'$  and  $\tan\delta$  are acceptable for ceramic capacitor applications [15]. However, the temperature coefficient of  $\epsilon'$  or capacitance is still one of the most important parameters to be considered before their use as materials to fabricate capacitors. Fig. 6 shows  $\Delta C/C$  (%) for the  $\text{La}^{3+}$ -doped CCTO ceramic samples compared to the value obtained at 20 °C and 1 kHz. It was found that the temperature coefficient of the La10 sample satisfies the EIA X5R capacitor specification, i.e.,  $\Delta C/C < \pm 15\%$  in the temperature range from −55–85 °C. Interestingly,  $\Delta C/C$  (%) of the La15 and La20 samples

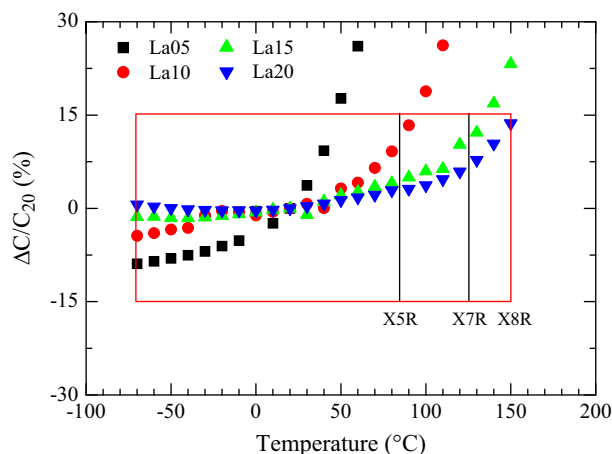


Fig. 6. Temperature coefficient of capacitance for La-doped CCTO ceramic samples in the temperature range of  $-70$ – $150$  °C evaluated at the frequency of 1 kHz.

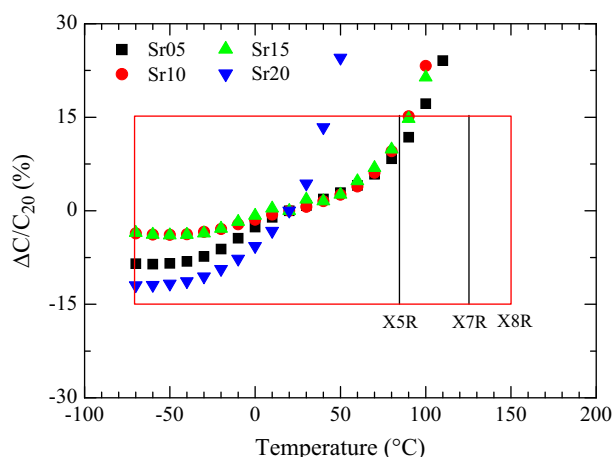


Fig. 7. Temperature coefficient of capacitance for Sr-doped CCTO ceramic samples in the temperature range of  $-70$ – $150$  °C evaluated at the frequency of 1 kHz.

were found to be  $< \pm 15\%$  over the temperature ranges of  $-55$ – $125$  °C and  $-55$ – $150$  °C, respectively. Therefore, the dielectric properties of the La15 and La20 samples satisfy the X7R and X8R capacitor specifications, respectively. This is the first report of CCTO with performance sufficient for fabrication of X8R capacitors. Fig. 7 shows  $\Delta C/C(\%)$  of the  $\text{Sr}^{2+}$ -doped CCTO ceramic samples. It was found that the condition of  $\Delta C/C < \pm 15\%$  for the Sr05, Sr10, and Sr15 samples occurred only in the range of  $-55$ – $85$  °C. This indicates that these three ceramics may have potential for fabrication of X5R capacitors. From the overall dielectric properties of the  $\text{La}^{3+}$ -doped CCTO and  $\text{Sr}^{2+}$ -doped CCTO ceramics, it can be postulated that if it is desirable to fabricate temperature stable capacitors without reducing their size, the former material group may be used. In contrast, if the goal is to reduce capacitor size and if performance at extra high temperatures is not necessary, the later material group may be satisfactory due to their high  $\epsilon'$  values.

In this work, we also investigated the effects of  $\text{La}^{3+}$  and  $\text{Sr}^{2+}$  doping ions on the nonlinear current–voltage properties of CCTO ceramics. As shown in Fig. 8, all ceramic samples

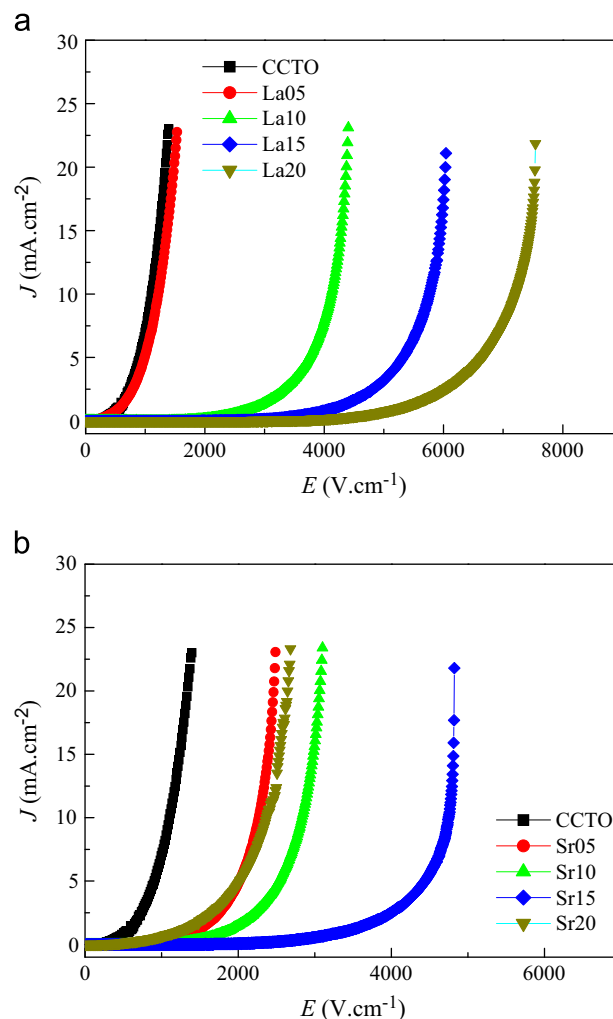


Fig. 8. Non-ohmic characteristics ( $J$  vs.  $E$ ) of (a) La-doped CCTO and (b) Sr-doped CCTO ceramics at room temperature.

exhibit non-ohmic properties.  $E_b$  and  $\alpha$  values were calculated from the  $J$ – $E$  curves. These calculated values for all samples are summarized in Table 1. It was found that both the  $E_b$  and  $\alpha$  values of the La10, La15, La20 samples as well as the Sr05, Sr10, Sr15 samples increased with increasing  $\text{La}^{3+}$  and  $\text{Sr}^{2+}$  concentrations.  $E_b$  and  $\alpha$  values of these samples were larger than the values of the undoped CCTO ceramic sample. It was observed that suitable doping concentration ranges of  $\text{La}^{3+}$  or  $\text{Sr}^{2+}$  exist for simultaneously improving both dielectric and nonlinear properties.

#### 4. Conclusion

We successfully improved the dielectric and nonlinear electrical properties of CCTO ceramics by substitution of  $\text{La}^{3+}$  or  $\text{Sr}^{2+}$ . The results revealed that these two substituted ions have different influences on the overall dielectric properties. It was found that doping with  $\text{La}^{3+}$  to CCTO ceramics can reduce  $\tan\delta$  ( $< 0.03$ ). Furthermore, this can cause an increase in the temperature–capacitance coefficient. A slight disadvantage of  $\text{La}^{3+}$  substitution is that  $\epsilon'$  of CCTO ceramics was

greatly reduced from  $\sim 17,500$  to  $\sim 5300$  and  $\sim 2700$  for  $\text{Ca}_{0.775}\text{La}_{0.15}\text{Cu}_3\text{Ti}_4\text{O}_{12}$  and  $\text{Ca}_{0.70}\text{La}_{0.2}\text{Cu}_3\text{Ti}_4\text{O}_{12}$  ceramics, respectively. However, these two ceramics still satisfied the EIA X7R and X8R temperature specifications for capacitor applications, respectively. Substitution of  $\text{Sr}^{2+}$  at concentrations of 5–15 at% can significantly reduce  $\tan\delta$  ( $< 0.04$ ). Interestingly,  $\epsilon'$  was slightly reduced and still found to be higher than  $10^4$ . The temperature-capacitance coefficients were found to be less than  $\pm 15\%$  in the range from  $-60$ – $90$  °C only. We also found that substitutions of  $\text{La}^{3+}$  and  $\text{Sr}^{2+}$  doping ions have remarkable effects on the nonlinear current-voltage properties of CCTO ceramics.

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